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1 A fault coverage-driven partial scan chain selection technique

Gloster, C., Jr.; Subramanian, S.;

ASIC Conference and Exhibit, 1994. Proceedings., Seventh Annual IEEE International, 19-23 Sept. 1994

Pages: 366 - 369

[Abstract] [PDF Full-Text (264 KB)]

2 A novel scan architecture for power-efficient, rapid test [sequential circuits]

Sinanoglu, O.; Orailoglu, A.;

Computer Aided Design, 2002. ICCAD 2002. IEEE/ACM International Conference on , 10-14 Nov. 2002

Pages: 299 - 303

[PDF Full-Text (450 KB)] [Abstract] **IEEE CNF**

3 Static test compaction for full-scan circuits based on combinational test sets and non-scan sequential test sequences

Pomeranz, I.; Reddy, S.M.;

VLSI Design, 2003. Proceedings. 16th International Conference on , 4-8 Jan. 2003

Pages: 335 - 340

[Abstract] [PDF Full-Text (247 KB)] **IEEE CNF**

4 Reducing test power during test using programmable scan chain disable Sankaralingam, R.; Touba, N.A.;

Electronic Design, Test and Applications, 2002. Proceedings. The First IEEE International Workshop on , 29-31 Jan. 2002

Pages: 159 - 163

[Abstract] [PDF Full-Text (266 KB)] **IEEE CNF**

5 Reducing power dissipation during test using scan chain disable Sankaralingam, R.; Pouya, B.; Touba, N.A.;

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[Abstract] [PDF Full-Text (536 KB)] IEEE CNF

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Ichino, K.; Asakawa, T.; Fukumoto, S.; Iwasaki, K.; Kajihara, S.; Test Symposium, 2001. Proceedings. 10th Asian, 19-21 Nov. 2001 Pages: 379 - 384

[Abstract] [PDF Full-Text (539 KB)] IEEE CNF

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Huan-Chih Tsai; Kwang-Ting Cheng; Bhawmik, S.; Design Automation Conference, 1999. Proceedings. 36th, 21-25 June 1999 Pages: 748 - 753

[Abstract] [PDF Full-Text (552 KB)] IEEE CNF

8 Full scan fault coverage with partial scan

Xijiang Lin; Pomeranz, I.; Reddy, S.M.;
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Proceedings, 9-12 March 1999
Pages: 468 - 472

[Abstract] [PDF Full-Text (180 KB)] IEEE CNF

9 A partial scan methodology for testing self-timed circuits

Khoche, A.; Brunvand, E.; VLSI Test Symposium, 1995. Proceedings., 13th IEEE, 30 April-3 May 1995 Pages: 283 - 289

[Abstract] [PDF Full-Text (612 KB)] IEEE CNF

10 Hypertasking: automatic array and loop partitioning on the iPSC Baber, M.;

System Sciences, 1991. Proceedings of the Twenty-Fourth Annual Hawaii International Conference on , Volume: ii , 8-11 Jan. 1991 Pages:438 - 447 vol.2

[Abstract] [PDF Full-Text (732 KB)] IEEE CNF

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